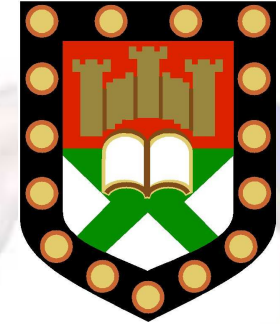


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# Rare earths in GaN

Jean-Sébastien Filhol<sup>1</sup>, M. Shaw<sup>2</sup>, P. Briddon<sup>2</sup>, R. Jones<sup>1</sup>

<sup>1</sup> Semiconductor department, School of Physics,  
University of Exeter, Exeter, U.K.

<sup>2</sup> School of Natural Science,  
University of Newcastle Upon Tyne, U.K.

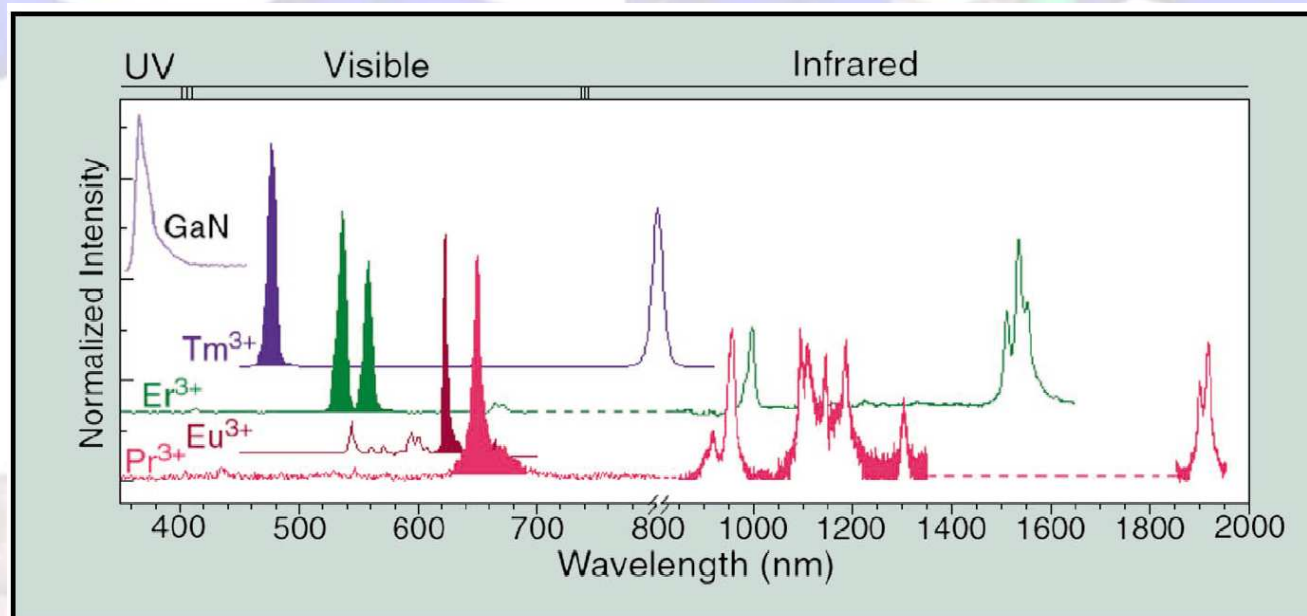
# Why rare earths in GaN ?

Rare earths intra f transitions are weakly dependant of the matrix

→ Using different R.E. allows to get the primary visible colors

→ Er has an emission at 154  $\mu\text{m}$

→ GaN:R.E. emission can still be strong at room temperature



Eu:	Red
Er:	Green (+IR)
Tm:	Blue

Emission spectrum of different rare earthes (R.E.) in GaN

(A.J. Steckl et al. Compound Semiconductor 2000 6(1) 48)

# Computational method

AIMPRO DFT package.

- periodic density functional theory calculations
- LDA approach
- local Gaussian basis set
- Monkhorst-Pack k-point sampling mesh (MP2 and MP4)
- Hartwigsen-Goedecker-Hutter (HGH) pseudopotentials
- unit cell: 72 atoms

Erbium f shell is kept frozen inside the core in R.E.<sup>3+</sup> structure

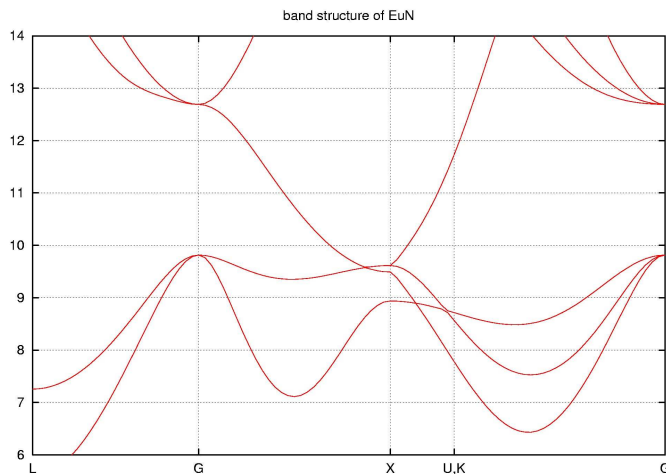
# Pseudopotential validation

## Rare earth nitride Nitride

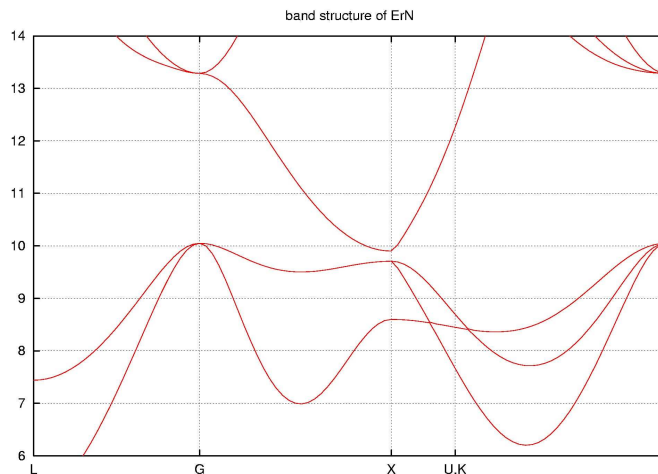
	EuN	ErN	TmN
Lattice parameter (exp.)	4.91 Å (5.01 Å)	4.74 Å (4.84 Å)	4.70 Å (4.81 Å)
Bulk modulus	179 GPa	195 GPa	201 GPa

Lattice error:  
 $\approx 2\%$

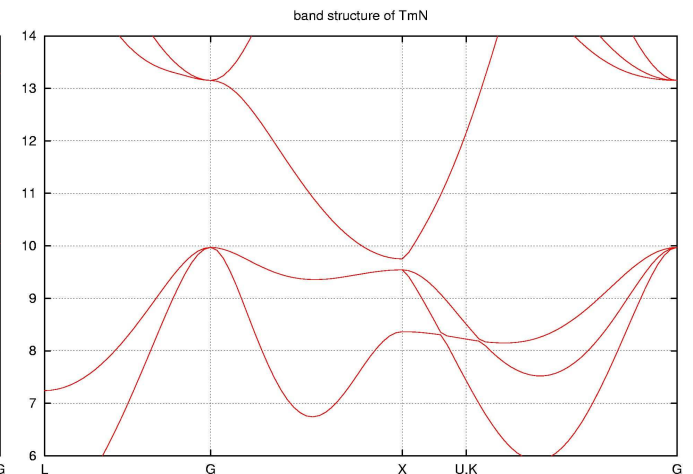
Band structure  
Equivalent to previous  
calculations  
 $\text{Eu} > \text{Er} > \text{Tm}$



EuN



ErN

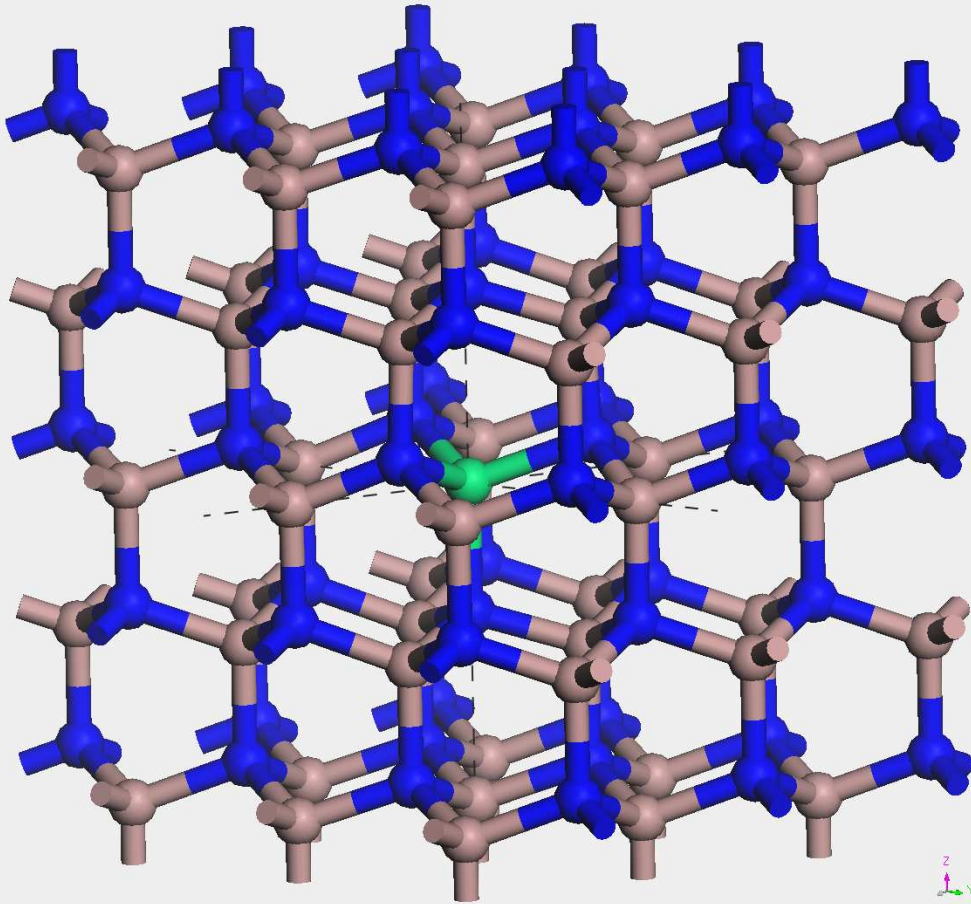


TmN

→ The nitride phase of the rare earths are metallic, semi-metallic or very low gap semiconductors: quench the luminescence



# Rare earths in GaN: substitutional Ga site



Er, Eu and Tm in Ga substitutional sites.

- the local symmetry is  $C_{3v}$
- compressive strain of the GaN lattice around the R.E.

- Er, Tm strain is 9%

- Eu strain is 12 %

# Geometry of the R.E. substitutional site

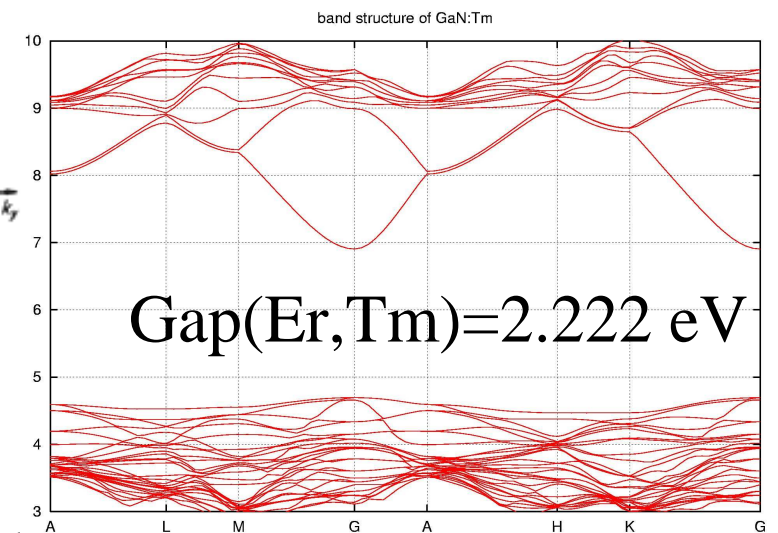
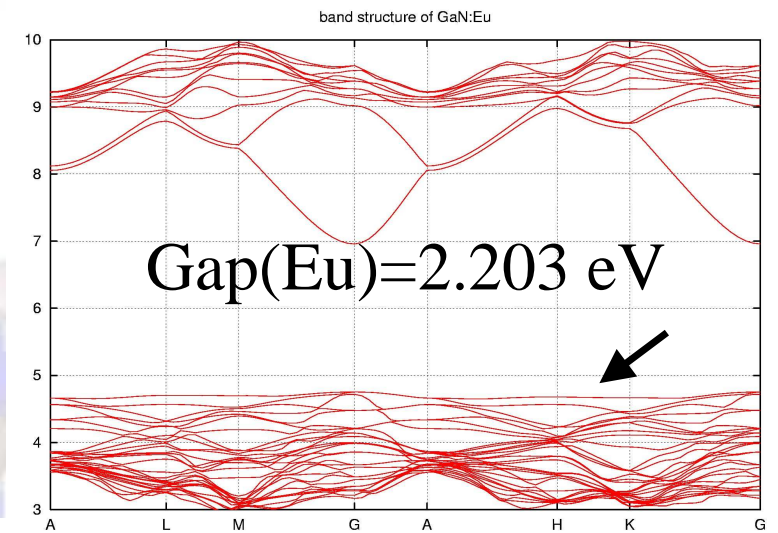
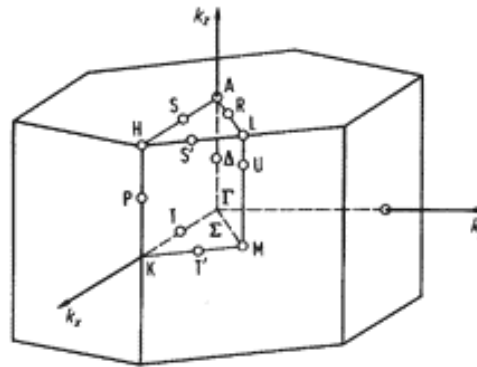
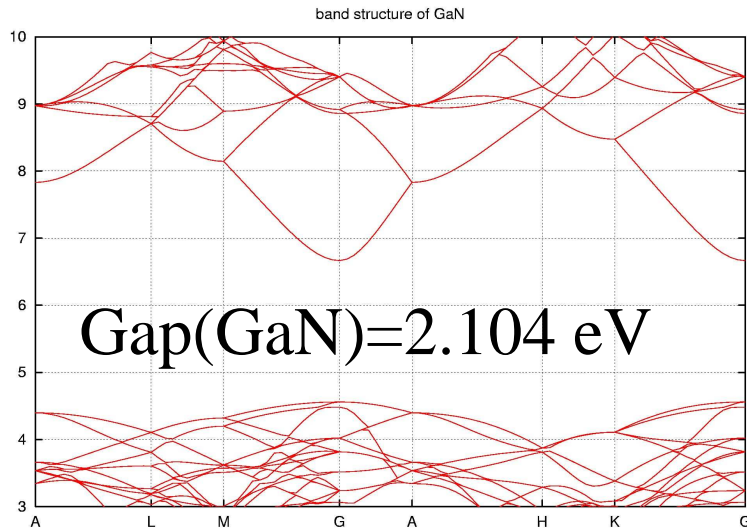
GaN:X	X-N <sub>1</sub> (3 bonds)	X-N <sub>2</sub> (1 bond)	X-Ga <sub>1</sub> (9 bonds)	X-Ga <sub>2</sub> (3 bonds)
GaN:Eu (exp.)	2.18 Å (2.26 Å) <sup>1</sup>	2.22 Å	3.23 Å (3.32 Å) <sup>1</sup>	3.27 Å
GaN:Er (exp.)	2.13 Å (2.17 Å) <sup>2</sup>	2.16 Å	3.22 Å (3.26 Å) <sup>2</sup>	3.26 Å
GaN:Tm	2.12 Å	2.15 Å	3.22 Å	3.25 Å

1. S. Morishima et al.  
internet publication...
2. Citrin et al. 2000  
Appl. Phys. Lett. vol  
76 p2865

Tm < Er < Eu

- Good agreement between the calculations and the EXAFS results
- Very short R.E.- N bond (0.2 Å shorter than in the R.E. Nitride)

# Electronic properties of R.E. in Ga site



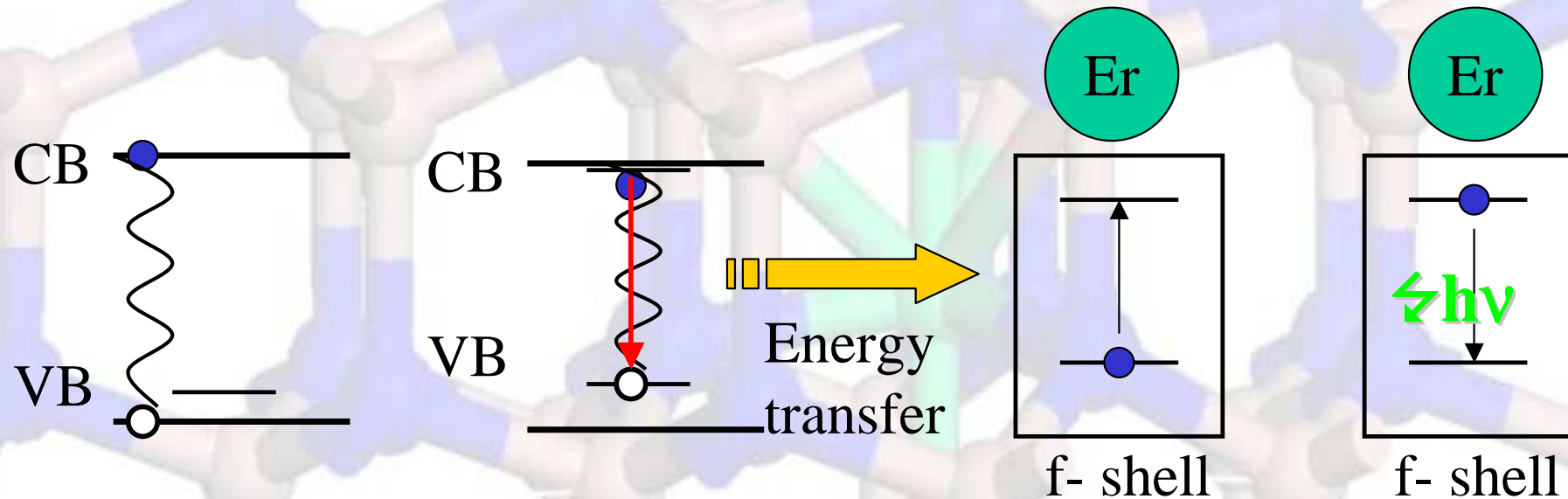
→ The effect of the R.E. in the Ga site is weak :

- small increase of the gap (DFT) by 0.1 eV
- the band structure only a little modified: level around at Fermi level (see around H)

→ very shallow donor above the VB?



# Rare earth luminescence in semiconductors



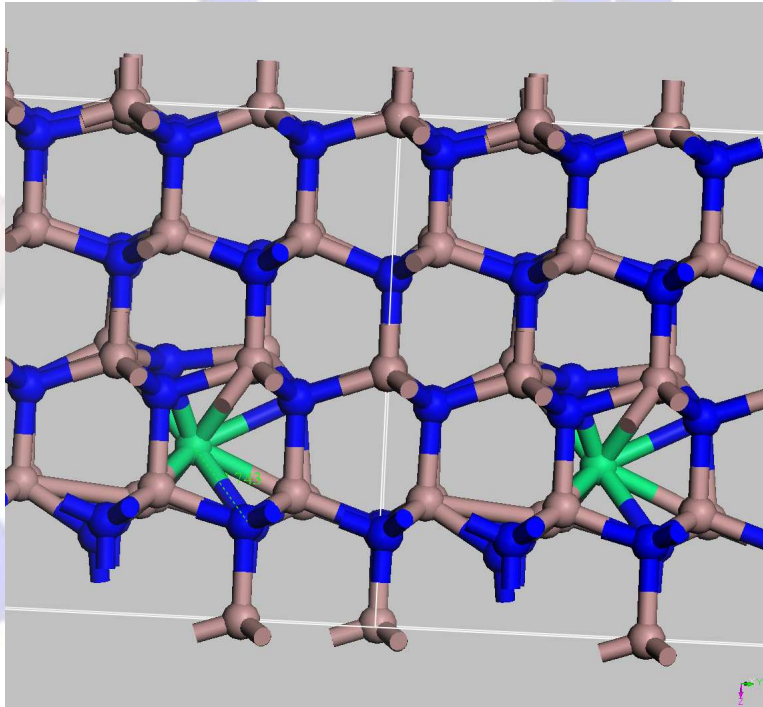
-Rare earth induced shallow donor level

→ exciton trap

→ low energy trap : high quenching with temperature increase



# R.E. in interstitial defects



Low local symmetry:  $C_{1h}$

The R.E. atom tends to displace a Ga



$$\Delta E (\text{Eu}) = -900 \text{ meV}$$

$$\Delta E (\text{Er}) = -640 \text{ meV}$$

$$\Delta E (\text{Tm}) = -630 \text{ meV}$$

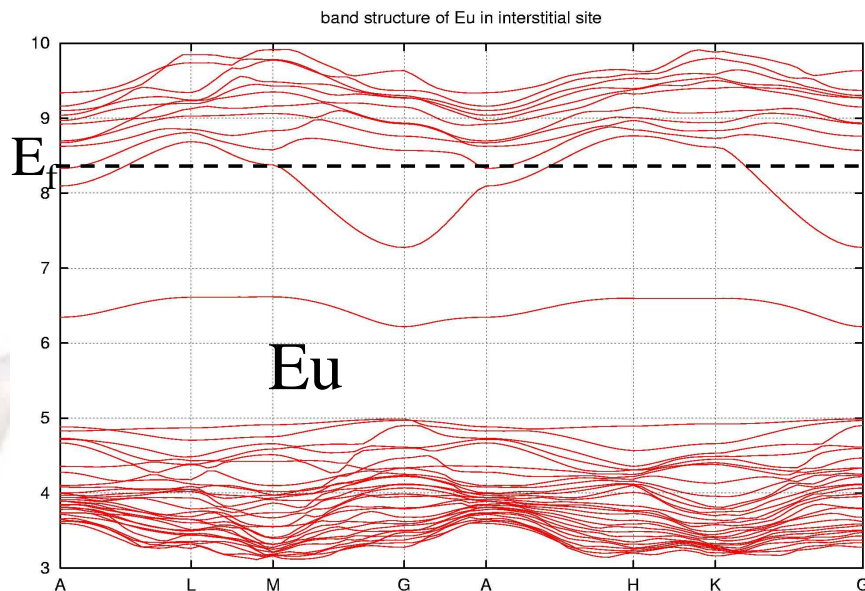
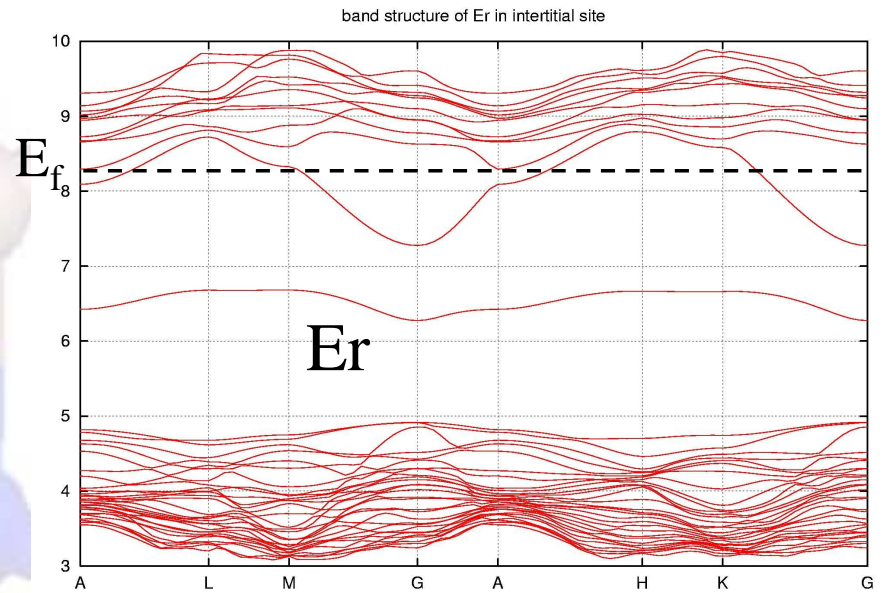
**Exothermic reaction**

(Å)	X-N <sub>1</sub>	X-N <sub>2</sub> (2)	X-N <sub>3</sub> (2)	X-Ga <sub>1</sub>	X-Ga <sub>2</sub> (2)	X-Ga <sub>3</sub> (2)
Eu	2.16	2.33	2.40	2.42	2.57	2.72
Er	2.11	2.29	2.35	2.38	2.54	2.70
Tm	2.10	2.28	2.35	2.37	2.54	2.69

→ R.E. atoms tend to be in substitutional Ga site in GaN

→ but interstitial structure gives a mid-gap level

# Electronic properties of R.E. in interstitial sites



- n type
- the gap is mostly unchanged
- shallow effective mass donor level
- interstitial structure present mid-gap donor

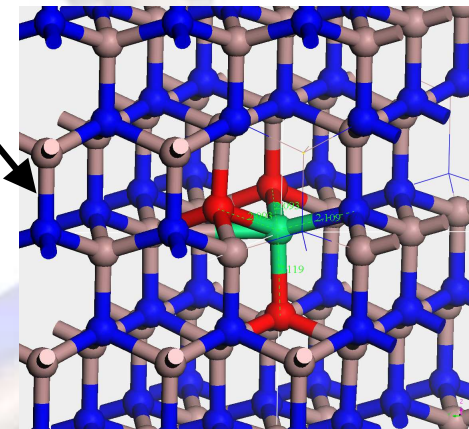
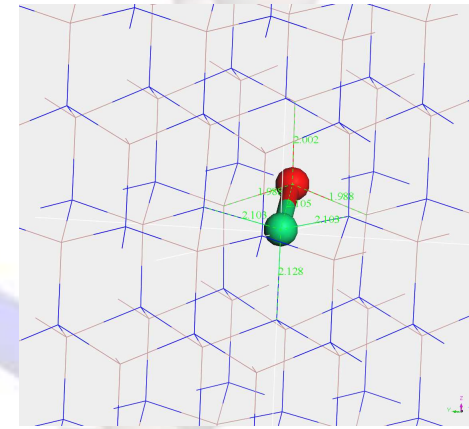
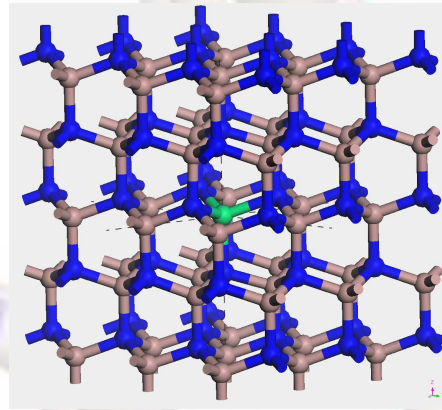
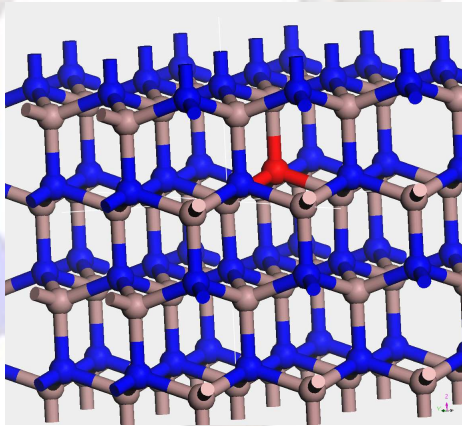
Candidate for the deep defect related with low quenching ?



# Interaction of Er with O in GaN

Study of O in N site and Er in Ga site

O-R.E. bonds are the only ones stronger than N- R.E.



## Structure

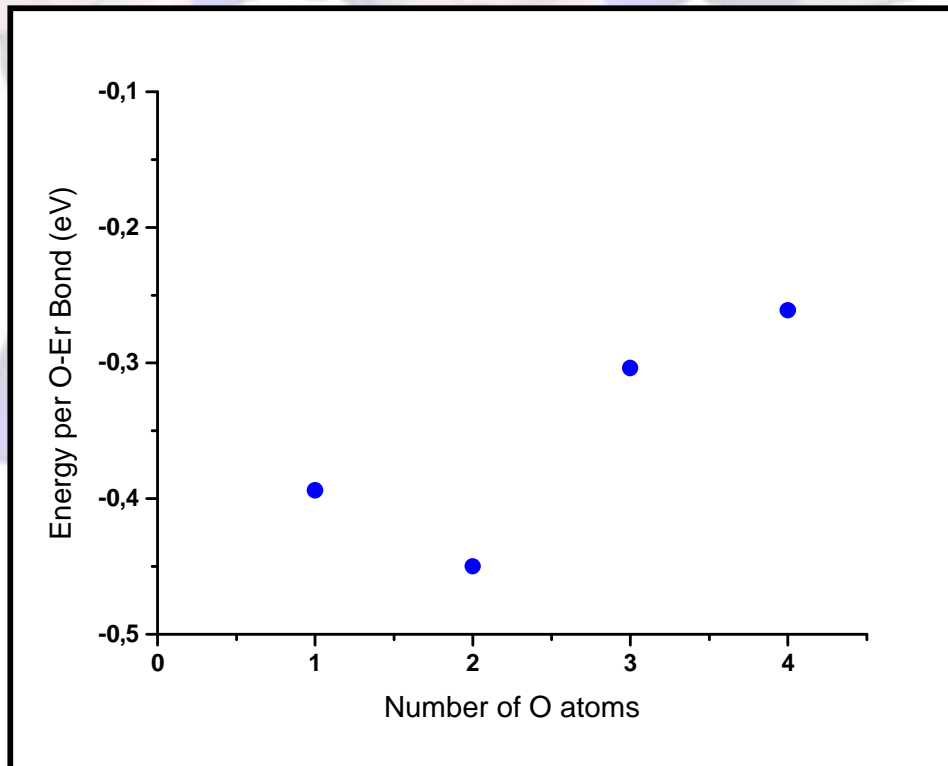
### ErO

Er-O: 2.11 Å, Er-N: 2.11 Å

### ErO<sub>3</sub>

Er-O: 2.10 Å, Er-N: 2.11 Å

# Formation of the $\text{ErO}_x$ clusters



The Er-O bond formation is much weaker than in Si:

- in Si, Er-O  $\approx$  3 eV

- in GaN, Er-O  $\approx$  0.4 eV

→ Er-N bond is already very strong

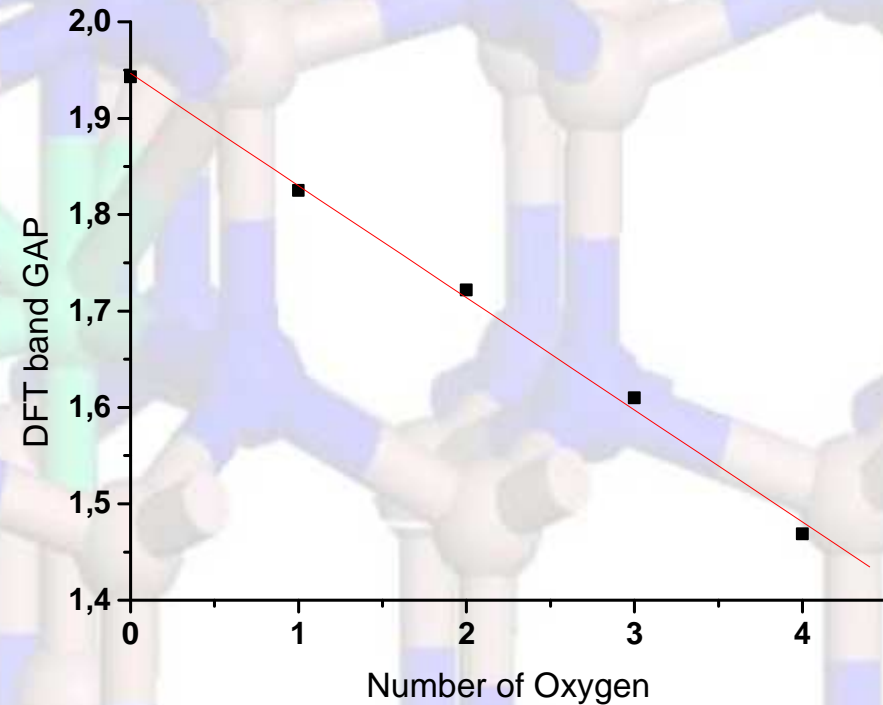
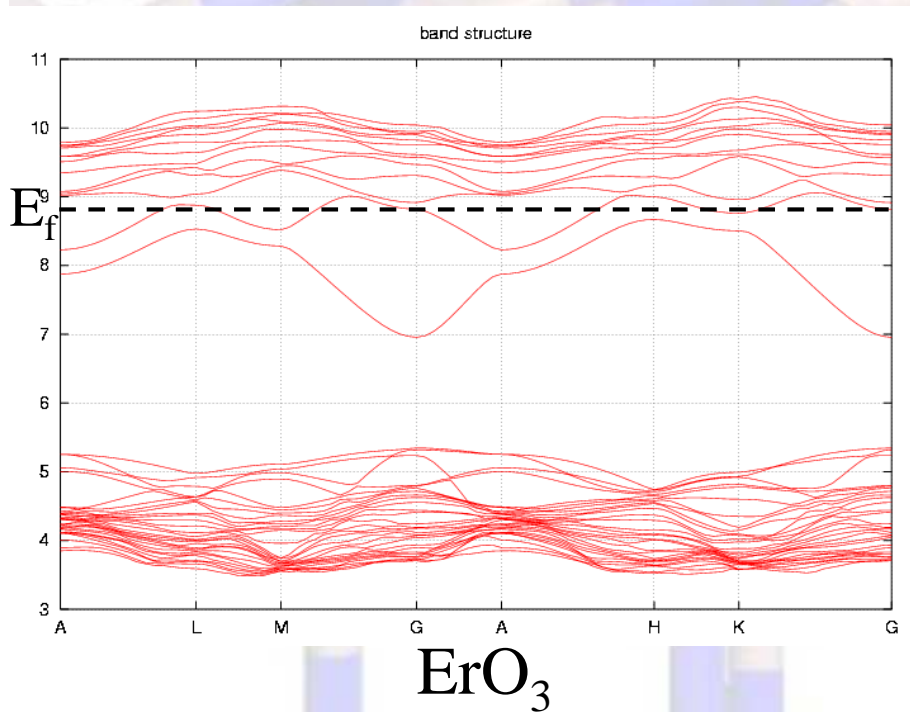
**$\text{ErO}_2$  are favoured structures**

→ The  $\text{ErO}_x$  formation is going to be sensitive to the annealing temperature

→  $\text{ErO}_2$  clusters are expected to form in GaN



# Electronic structure of ErOx in GaN



- O in GaN is a n type dopant:
- Linear decrease of the band gap with the amount of O
  - Shallow to deep level in the band gap (ErO<sub>2</sub> shows a gap decrease of 0.2 eV)

# Conclusion of R.E. in GaN

## **R.E. in a Ga site weakly modify the structure of GaN:**

- R.E. tends to be in a Ga site.
- Er (in Ga site) doesn't modify the GaN structure much
- limited stress caused by R.E. (only 12% strain in the R.E.-N)

R.E. are easily incorporated in GaN

## **R.E. in interstitial site induce mid-gap levels**

## **The affinity of Er for O is weak in GaN**

- Er – O interaction exists in GaN

$\text{ErO}_x$  structures are expected in GaN

The theoretical calculations seem to reproduce well the behaviour of R.E. in GaN.

Perspective: R.E. interaction with vacancies and C.